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# PBSS4032ND

 $30 \text{ V}, 3.5 \text{ A NPN low V}_{\text{CEsat}}$  (BISS) transistor Rev. 01 — 30 January 2010

**Product data sheet** 

### **Product profile**

### 1.1 General description

NPN low V<sub>CEsat</sub> Breakthrough In Small Signal (BISS) transistor in a SOT457 (SC-74) small Surface-Mounted Device (SMD) plastic package.

PNP complement: PBSS4032PD.

#### 1.2 Features

- Low collector-emitter saturation voltage V<sub>CEsat</sub>
- Optimized switching time
- High collector current capability I<sub>C</sub> and I<sub>CM</sub>
- High collector current gain (h<sub>FE</sub>) at high I<sub>C</sub>
- High energy efficiency due to less heat generation
- AEC-Q101 qualified
- Smaller required Printed-Circuit Board (PCB) area than for conventional transistors

### 1.3 Applications

- DC-to-DC conversion
- Battery-driven devices
- Power management
- Charging circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{CEO}$	collector-emitter voltage	open base	-	-	30	V
I <sub>C</sub>	collector current		-	-	3.5	Α
I <sub>CM</sub>	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	-	6	Α
R <sub>CEsat</sub>	collector-emitter saturation resistance	I <sub>C</sub> = 4 A; I <sub>B</sub> = 400 mA	<u>[1]</u> _	50	75	mΩ

<sup>[1]</sup> Pulse test:  $t_p \le 300~\mu s;~\delta \le 0.02.$ 



## 2. Pinning information

Table 2. Pinning

	•		
Pin	Description	Simplified outline	Graphic symbol
1	collector	G. G. G.	
2	collector	<u> </u>	1, 2, 5, 6 
3	base		3 —
4	emitter	1 12 13	
5	collector		4 sym014
6	collector		oyme 14

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PBSS4032ND	SC-74	plastic surface-mounted package; 6 leads	SOT457

## 4. Marking

Table 4. Marking codes

Type number	Marking code
PBSS4032ND	ZF

# 5. Limiting values

Table 5. Limiting values

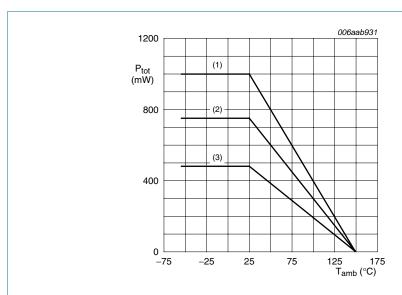
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{\text{CBO}}$	collector-base voltage	open emitter	-	30	V
$V_{CEO}$	collector-emitter voltage	open base	-	30	V
$V_{EBO}$	emitter-base voltage	open collector	-	5	V
I <sub>C</sub>	collector current		-	3.5	Α
I <sub>CM</sub>	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	6	Α
I <sub>B</sub>	base current		-	0.5	Α

**Table 5.** Limiting values ...continued
In accordance with the Absolute Maximum Rating System (IEC 60134).

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Symbol	Parameter	Conditions	Min	Max	Unit
P <sub>tot</sub>	total power dissipation	$T_{amb} \leq 25 ^{\circ}C$	<u>[1]</u> -	480	mW
			[2] _	750	mW
			[3] _	1	W
T <sub>j</sub>	junction temperature		-	150	°C
T <sub>amb</sub>	ambient temperature		-55	+150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- [3] Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.



- (1) Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint
- (2) FR4 PCB, mounting pad for collector 6 cm<sup>2</sup>
- (3) FR4 PCB, standard footprint

Fig 1. Power derating curves

#### **Thermal characteristics** 6.

Table 6. **Thermal characteristics** 

Symbol	Parameter	Conditions	ľ	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from	in free air	<u>[1]</u> -	-	-	260	K/W
j	junction to ambient		[2] -	•	-	160	K/W
			[3] _	•	-	125	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	-	45	K/W

- Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.

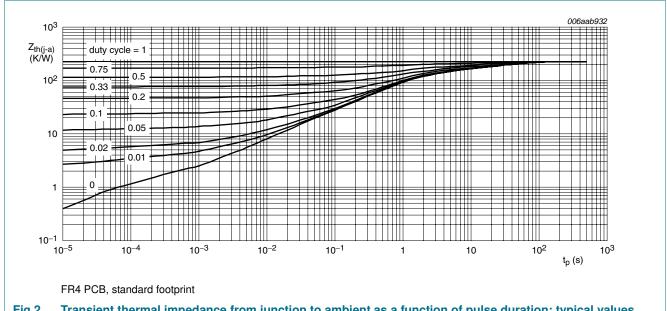
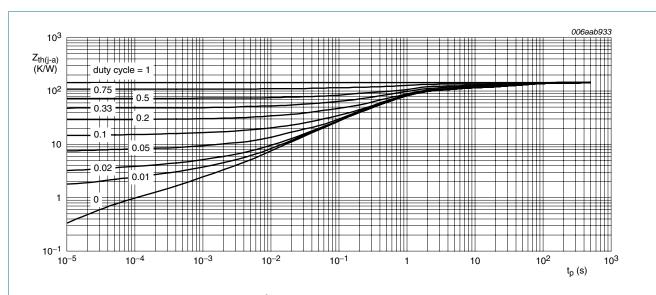
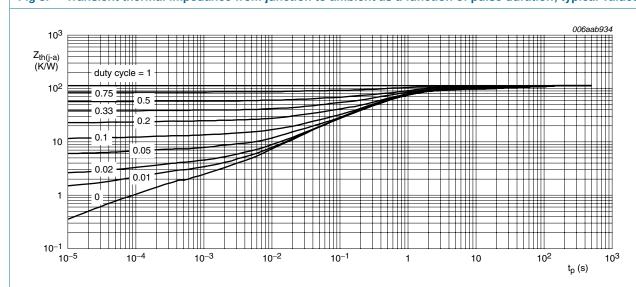


Fig 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for collector 6 cm<sup>2</sup>

Fig 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

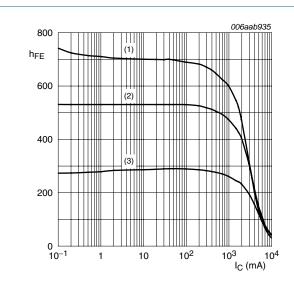
## 7. Characteristics

**Table 7. Characteristics** 

T<sub>amb</sub> = 25 °C unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I <sub>CBO</sub>	collector-base cut-off	$V_{CB} = 30 \text{ V}; I_E = 0 \text{ A}$		-	-	100	nA
	current	$V_{CB} = 30 \text{ V}; I_E = 0 \text{ A};$ $T_j = 150 ^{\circ}\text{C}$		-	-	50	μА
I <sub>CES</sub>	collector-emitter cut-off current	$V_{CE} = 24 \text{ V}; V_{BE} = 0 \text{ V}$		-	-	100	nA
I <sub>EBO</sub>	emitter-base cut-off current	$V_{EB} = 5 \text{ V}; I_{C} = 0 \text{ A}$		-	-	100	nA
h <sub>FE</sub>	DC current gain	$V_{CE} = 2 \text{ V}; I_{C} = 500 \text{ mA}$	[1]	300	500	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 1 A	[1]	300	460	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 2 A	[1]	250	400	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 4 A	[1]	120	200	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 6 A	[1]	60	100	-	
V <sub>CEsat</sub>	collector-emitter	$I_C = 500 \text{ mA}; I_B = 50 \text{ mA}$	[1]	-	70	100	mV
	saturation voltage	$I_C = 1 A$ ; $I_B = 50 \text{ mA}$	[1]	-	110	155	mV
		I <sub>C</sub> = 1 A; I <sub>B</sub> = 10 mA	[1]	-	155	220	mV
		$I_C = 2 A$ ; $I_B = 40 \text{ mA}$	[1]	-	180	250	mV
		$I_C = 3 A$ ; $I_B = 300 \text{ mA}$	[1]	-	180	250	mV
	I <sub>C</sub> = 4 A; I <sub>B</sub> = 400 mA	[1]	-	200	300	mV	
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_C = 4 \text{ A}; I_B = 400 \text{ mA}$	[1]	-	50	75	mΩ
V <sub>BEsat</sub>	base-emitter	$I_C = 1 A; I_B = 100 mA$	[1]	-	0.78	0.9	٧
	saturation voltage	$I_C = 3 \text{ A}; I_B = 300 \text{ mA}$	[1]	-	0.98	1.1	٧
$V_{BEon}$	base-emitter turn-on voltage	$V_{CE} = 2 \text{ V}; I_{C} = 2 \text{ A}$		-	0.79	0.85	V
t <sub>d</sub>	delay time	$V_{CC} = 12.5 \text{ V}; I_C = 1 \text{ A};$		-	23	-	ns
t <sub>r</sub>	rise time	$I_{Bon} = 0.05 \text{ A};$		-	25	-	ns
t <sub>on</sub>	turn-on time	$I_{Boff} = -0.05 \; A$		-	48	-	ns
t <sub>s</sub>	storage time			-	140	-	ns
t <sub>f</sub>	fall time			-	65	-	ns
t <sub>off</sub>	turn-off time			-	205	-	ns
f <sub>T</sub>	transition frequency	V <sub>CE</sub> = 10 V; I <sub>C</sub> = 100 mA; f = 100 MHz		-	135	-	MHz
C <sub>c</sub>	collector capacitance	$V_{CB} = 10 \text{ V}; I_E = i_e = 0 \text{ A};$ f = 1 MHz		-	44	-	pF

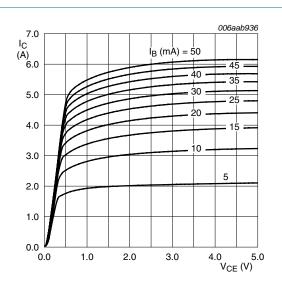
<sup>[1]</sup> Pulse test:  $t_p \leq 300~\mu s;~\delta \leq 0.02.$ 



$$V_{CE} = 2 V$$

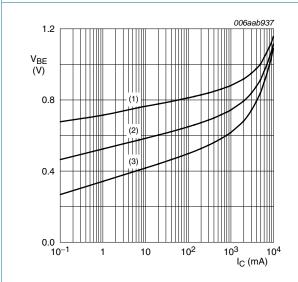
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

Fig 5. DC current gain as a function of collector current; typical values



 $T_{amb} = 25 \, ^{\circ}C$ 

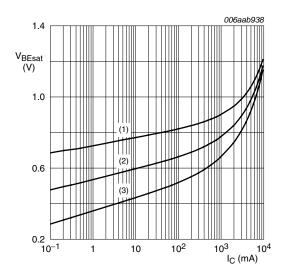
Fig 6. Collector current as a function of collector-emitter voltage; typical values





- (1)  $T_{amb} = -55 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

Fig 7. Base-emitter voltage as a function of collector current; typical values

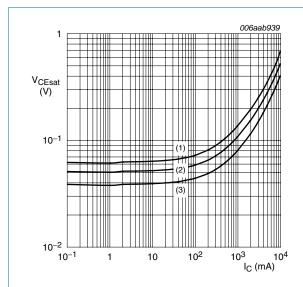


 $I_{\rm C}/I_{\rm B} = 20$ 

- (1)  $T_{amb} = -55 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

Fig 8. Base-emitter saturation voltage as a function of collector current; typical values

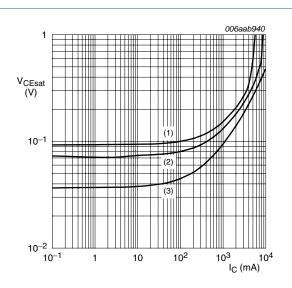
30 V, 3.5 A NPN low  $V_{\text{CEsat}}$  (BISS) transistor



$$I_C/I_B = 20$$

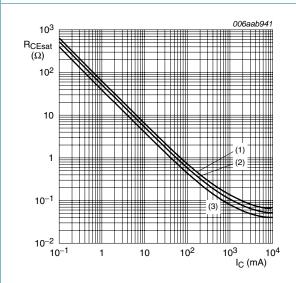
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

Fig 9. Collector-emitter saturation voltage as a function of collector current; typical values



- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

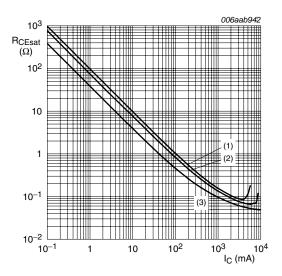
Fig 10. Collector-emitter saturation voltage as a function of collector current; typical values





- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

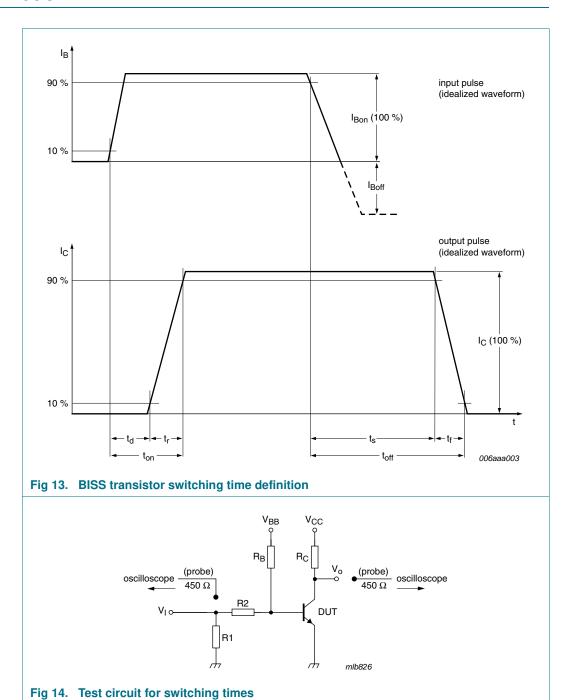
Fig 11. Collector-emitter saturation resistance as a function of collector current; typical values



- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

Fig 12. Collector-emitter saturation resistance as a function of collector current; typical values

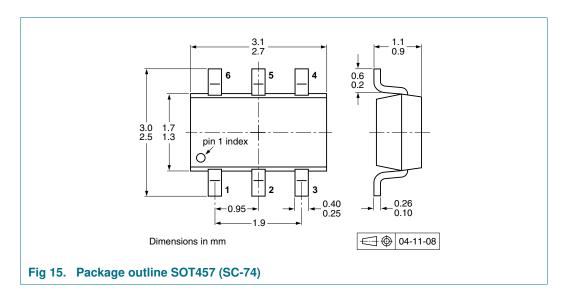
### 8. Test information



## 8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

## 9. Package outline



## 10. Packing information

Table 8. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

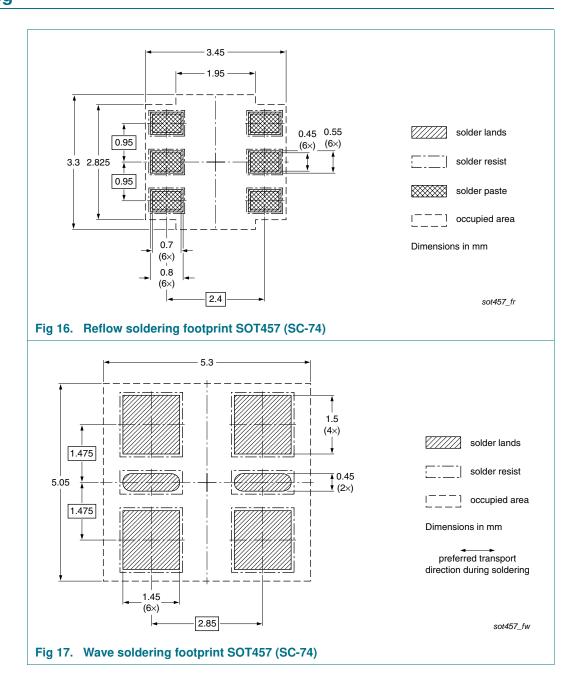
Type number	Package	Package Description		Packing quantity		
				3000	10000	
PBSS4032ND SOT457		4 mm pitch, 8 mm tape and reel	[2]	-115	-135	
		4 mm pitch, 8 mm tape and reel	[3]	-215	-235	

[1] For further information and the availability of packing methods, see Section 14.

[2] T1: normal taping

[3] T2: reverse taping

## 11. Soldering





# 12. Revision history

### Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PBSS4032ND_1	20100130	Product data sheet	-	-

### 13. Legal information

#### 13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
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# PBSS4032ND

### 30 V, 3.5 A NPN low V<sub>CEsat</sub> (BISS) transistor

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